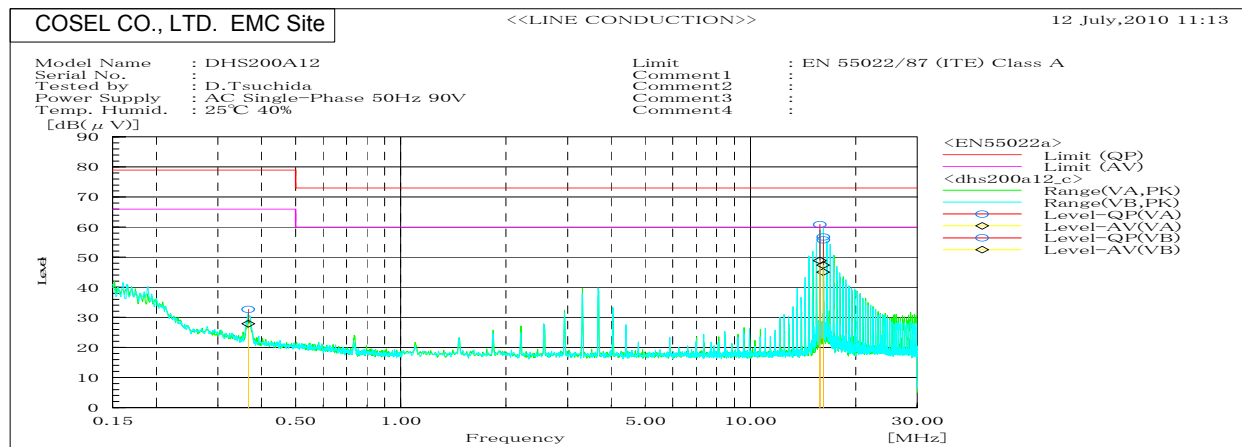
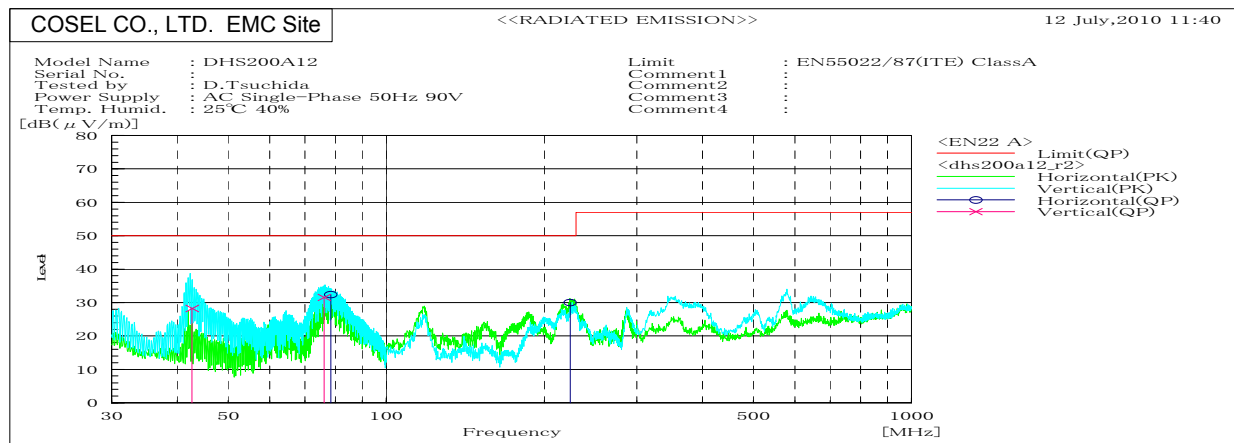


DATA SHEET		Date	10-Aug-10
Model	DHS200A12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida



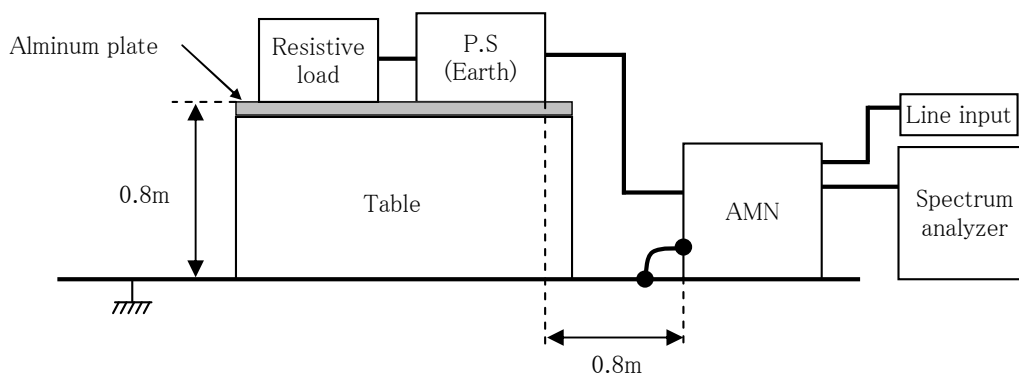
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.36637		VB	22.6	17.9	10	32.6	27.9	79	66	46.4	38.1	Pass	
15.7742		VB	50.2	38.3	10.6	60.8	48.9	73	60	12.2	11.1	Pass	
16.1503		VB	46.1	36.8	10.6	56.7	47.4	73	60	16.3	12.6	Pass	
16.143		VA	45.2	34.4	10.6	55.8	45	73	60	17.2	15	Pass	



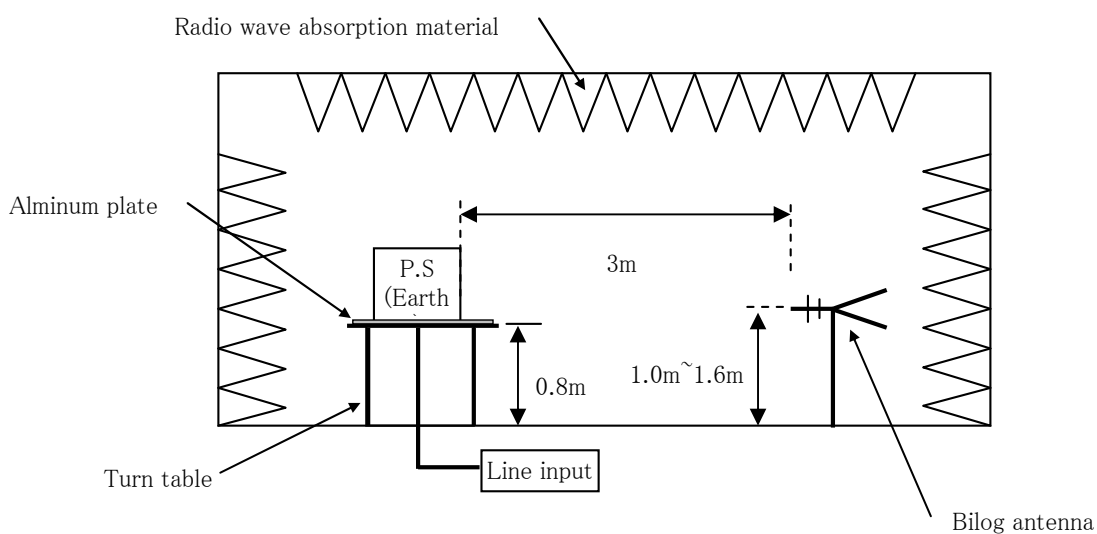
Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
42.702	V	Stable	48.5	-20.2		28.3		50	21.7	Pass	113	39
76.185	V	Stable	56.3	-24.8		31.5		50	18.5	Pass	134	292
78.432	H	Stable	57	-24.6		32.4		50	17.6	Pass	158	186
223.862	H	Stable	51.2	-21.2		30		50	20	Pass	110	150

DATA SHEET		Date	10-Aug-10
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida

1. Line conduction



2. Radiated emission

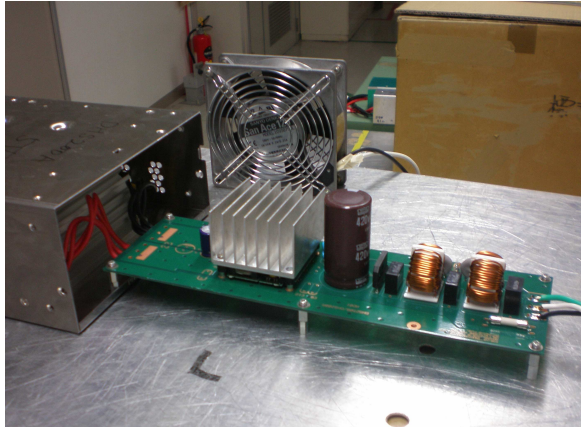


Test: EMI

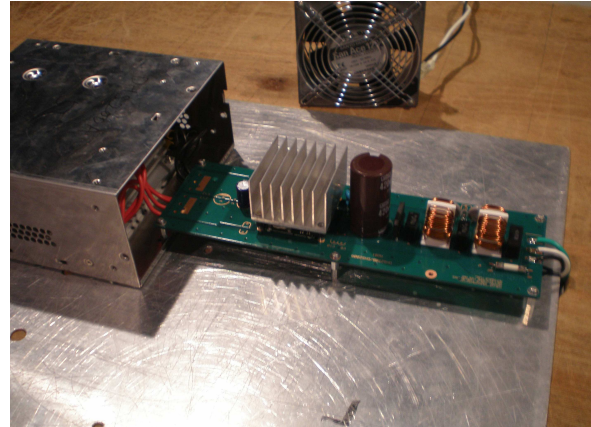
Model Name:DHS200A Series

○ Photographs of Test Set-Up

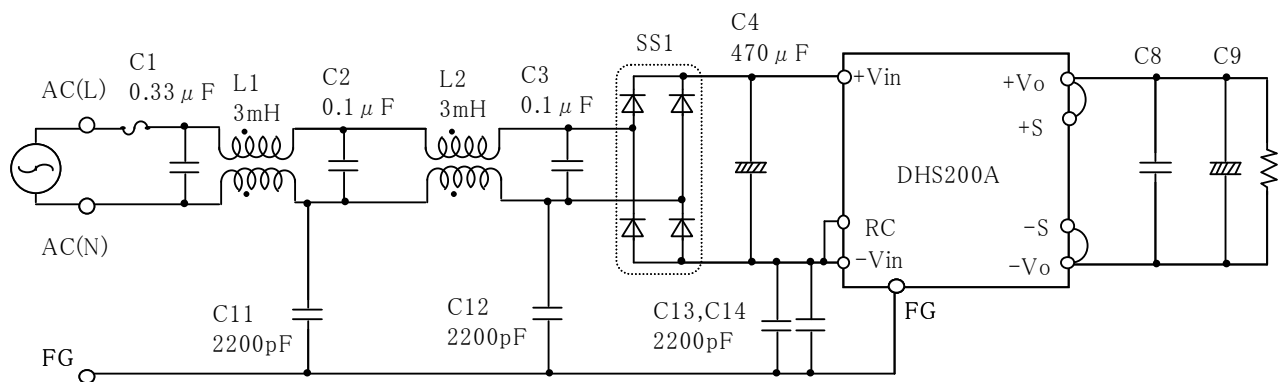
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



L1,L2 : SC-10-300(NEC TOKIN)

SS1 : D10XB60(SINDENGEN)

C8 : DHS200A05	10 μ F	C9 : DHS200A05	2200 μ F
DHS200A12	10 μ F	DHS200A12	1000 μ F
DHS200A15	10 μ F	DHS200A15	1000 μ F
DHS200A24	4.7 μ F	DHS200A24	470 μ F